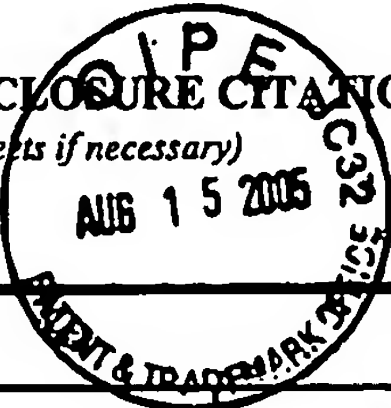


INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) YOR920030203US1 (16694)		Application Number 10/662,028	
				Applicant(s) Stephen W. Bedell, et al.			
				Filing Date September 12, 2003		Group Art Unit 3661 1742	



U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
GW		4,104,090	08/01/1978	Pogge, et al.			
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U.S. PATENT APPLICATION PUBLICATIONS							
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS		(Including Author, Title, Date, Pertinent Pages, Etc.)
GW		Mizuno, et al., "High Performance CMOS Operation of Strained-SOI MOSFETs Using Thin Film SiGe-On-Insulator Substrate", 2002 Symposium on VLSI Technology, Digest of Technical Papers, Honolulu, June 11-13, 2002, Symposium on VLSI Technology, New York, NY: IEEE, US, June 11, 2002, pp. 106-107, XP001109839
GW		Patent Abstracts of Japan, Vol. 005, No. 181 (E-083), November 20, 1981, 56-110247.

EXAMINER <div style="text-align: center; font-size: 1.5em; font-family: cursive;">GW</div>	DATE CONSIDERED <div style="text-align: center; font-size: 1.5em; font-family: cursive;">8/19/05</div>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) YOR920030203US1 (16694)		Application Number 10/662,028	
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FOREIGN PATENT DOCUMENTS								
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS			<i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>
<div style="font-size: 2em; font-family: cursive;">a</div>		Patent Abstracts of Japan, Vol. 005, No. 117 (E-067), May 18, 1981, 56-056648.	

EXAMINER <div style="font-size: 1.5em; font-family: cursive;">G. W. [Signature]</div>	DATE CONSIDERED <div style="font-size: 1.5em; font-family: cursive;">8/19/05</div>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.